

PATENT APPLICATION  
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Takashi IGARASHI et al.

Application No.: 10/611,918

Filed: July 3, 2003

For: LENS MACHINING APPARATUS, LENS MACHINING METHOD, AND LENS  
MEASUREMENT METHOD

FAX RECEIVED

Group Art Unit: 3723

FEB 06 2007

Examiner: H. SHAKER OFFICE OF PETITIONS

Docket No.: 108833.01

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed with a Request for Continued Examination. No certification or fee is required.
- 2. An English language Abstract of one or more non-English language reference is attached hereto. See References 2 and 3.
- 3. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 1 and 3.

Respectfully submitted,

*Leana Levin*

James A. Oliff  
Registration No. 27,075

Leana Levin  
Registration No. 51,939

JAO:LL/can

Date: February 6, 2007

OLIFF & BERRIDGE, PLC  
P.O. Box 19928  
Alexandria, Virginia 22320  
Telephone: (703) 836-6400

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Sheet 1 of 1

INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)			ATTY DOCKET NO. 108833.01	APPLICATION NO. 10/674,817 <b>FAX RECEIVED</b>  FEB 06 2007	
			APPLICANT(S) Takashi IGAKASHI et al.	OFFICE OF PETITIONS	
			FILING DATE July 3, 2003	GROUP 3723	
<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initials	Cite No.	Document Number	Date	Name	
<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract With English Translation
	1	JP-U-06-17853	3/18/1994	Japan	X
	2	JP-A-64-16346	1/19/1989	Japan	X
	3	JP-A-07-40191	2/10/1995	Japan	X X
<b>OTHER DOCUMENTS</b>					
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)			
EXAMINER				DATE CONSIDERED	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

Date: February 6, 2007